### **MAXIMUM RATINGS**

Symbol	Paramet	er	Value	Unit
V <sub>CC</sub>	DC Supply Voltage		-0.5 to +7.0	V
VI	DC Input Voltage		$-0.5 \le V_{\text{I}} \le V_{\text{CC}} + 0.5$	V
Vo	DC Output Voltage	(Note 1)	$-0.5 \le V_{O} \le V_{CC} + 0.5$	V
I <sub>IK</sub>	DC Input Diode Current		±20	mA
lok	DC Output Diode Current		±50	mA
I <sub>O</sub>	DC Output Sink/Source Current		±50	mA
I <sub>CC</sub>	DC Supply Current per Output Pin		±50	mA
I <sub>GND</sub>	DC Ground Current per Output Pin		±50	mA
T <sub>STG</sub>	Storage Temperature Range		-65 to +150	°C
TL	Lead temperature, 1 mm from Case for 10	Seconds	260	°C
TJ	Junction temperature under Bias		+150	°C
$\theta_{JA}$	Thermal resistance	PDIP SOIC	67 96	°C/W
$P_{D}$	Power Dissipation in Still Air at 85°C	PDIP SOIC	750 500	mW
MSL	Moisture Sensitivity		Level 1	
F <sub>R</sub>	Flammability Rating	Oxygen Index: 30% – 35%	UL 94 V-0 @ 0.125 in	
V <sub>ESD</sub>	ESD Withstand Voltage	Human Body Model (Note 2) Machine Model (Note 3) Charged Device Model (Note 4)	> 2000 > 200 > 1000	V
I <sub>Latchup</sub>	Latchup Performance Above V	CC and Below GND at 85°C (Note 5)	±100	mA

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- 1. I<sub>O</sub> absolute maximum rating must be observed.
- 2. Tested to EIA/JESD22-A114-A.
- 3. Tested to EIA/JESD22-A115-A.
- Tested to JESD22-C101-A.
- 5. Tested to EIA/JESD78.

### RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Min	Тур	Max	Unit
V <sub>CC</sub>	DC Input Voltage (Referenced to GND)	4.5		5.5	V
V <sub>in</sub> , V <sub>out</sub>	DC Input Voltage, Output Voltage (Referenced to GND)			V <sub>CC</sub>	V
T <sub>A</sub>	Operating Temperature, All Package Types	-40	25	+85	°C
t <sub>r</sub> , t <sub>f</sub>	Input Rise and Fall Time (Note 7) $ V_{CC} = 4.5 $ $ V_{CC} = 5.5 $	V 0 V 0	10 8.0	10 8.0	ns/V
T <sub>J</sub>	Junction Temperature (PDIP)			140	°C
I <sub>OH</sub>	Output Current – High			-24	mA
I <sub>OL</sub>	Output Current – Low			24	mA

<sup>6.</sup> Unused Inputs may not be left open. All inputs must be tied to a high voltage level or low logic voltage level.
7. V<sub>in</sub> from 0.8 V to 2.0 V; refer to individual Data Sheets for devices that differ from the typical input rise and fall times.

### **DC CHARACTERISTICS**

		V <sub>CC</sub>	T <sub>A</sub> = -	+25°C	T <sub>A</sub> = -40°C to +85°C		
Symbol	Parameter	(V)	Typ Guara		inteed Limits	Unit	Conditions
V <sub>IH</sub>	Minimum High Level Input Voltage	4.5 5.5	1.5 1.5	2.0 2.0	2.0 2.0	V V	V <sub>OUT</sub> = 0.1 V or V <sub>CC</sub> - 0.1 V
V <sub>IL</sub>	Maximum Low Level Input Voltage	4.5 5.5	1.5 1.5	0.8 0.8	0.8 0.8	V V	V <sub>OUT</sub> = 0.1 V or V <sub>CC</sub> - 0.1 V
V <sub>OH</sub>	Minimum High Level Output Voltage	4.5 5.5	4.49 5.49	4.4 5.4	4.4 5.4	V V	I <sub>OUT</sub> = -50 μA
		4.5 5.5		3.86 4.86	3.76 4.76	V V	$^*$ V <sub>IN</sub> = V <sub>IL</sub> or V <sub>IH</sub> $-24$ mA $_{OH}$ $-24$ mA
V <sub>OL</sub>	Maximum Low Level Output Voltage	4.5 5.5	0.001 0.001	0.1 0.1	0.1 0.1	V V	I <sub>OUT</sub> = 50 μA
		4.5 5.5		0.36 0.36	0.44 0.44	V V	$^*$ V <sub>IN</sub> = V <sub>IL</sub> or V <sub>IH</sub> $-24$ mA $_{OH}$ $-24$ mA
I <sub>IN</sub>	Maximum Input Leakage Current	5.5		±0.1	±1.0	μΑ	$V_I = V_{CC}$ , GND
$\Delta I_{CCT}$	Additional Max. I <sub>CC</sub> /Input	5.5	0.6		1.5	mA	V <sub>I</sub> = V <sub>CC</sub> – 2.1 V
I <sub>OZ</sub>	Maximum 3–State Current	5.5		±0.5	±5.0	μΑ	$ \begin{array}{c} V_{I} \; (OE) = V_{IL},  V_{IH} \\ V_{I} = V_{CC},  GND \\ V_{O} = V_{CC},  GND \end{array} $
I <sub>OLD</sub> I <sub>OHD</sub>	†Minimum Dynamic Output Current	5.5 5.5			75 –75	mA mA	V <sub>OLD</sub> = 1.65 V Max
I <sub>CC</sub>	Maximum Quiescent Supply Current	5.5		8.0	80	μΑ	V <sub>IN</sub> = V <sub>CC</sub> or GND

<sup>\*</sup>All outputs loaded; thresholds on input associated with output under test. †Maximum test duration 2.0 ms, one output loaded at a time.

# AC CHARACTERISTICS $t_r = t_f = 3.0$ ns (For Figures and Waveforms, See Figures 2 and 3.)

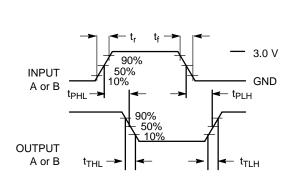
			V <sub>CC</sub> *	T <sub>A</sub> = +25°C C <sub>L</sub> = 50 pF		$T_A = -40$ °C to +85°C $C_L = 50 \text{ pF}$		
Symbol	Para	ameter	(V)	Min	Max	Min	Max	Unit
t <sub>PLH</sub>	Propagation Delay	An to Bn or Bn to An	5.0	1.5	8.0	1.0	8.5	ns
t <sub>PHL</sub>	Propagation Delay	An to Bn or Bn to An	5.0	1.5	8.0	1.0	9.0	ns
t <sub>PZH</sub>	Output Enable Time	OE to An or Bn	5.0	1.5	10.0	1.0	11.0	ns
t <sub>PZL</sub>	Output Enable Time	OE to An or Bn	5.0	1.5	10.0	1.0	11.0	ns
t <sub>PHZ</sub>	Output Disable Time	T/R or OE to An or Bn	5.0	1.5	10.0	1.0	11.0	ns
t <sub>PLZ</sub>	Output Disable Time	T/R or OE to An or Bn	5.0	1.5	10.0	1.0	11.0	ns

<sup>\*</sup>Voltage Range 5.0 V is 5.0 V ±0.5 V

## **CAPACITANCE**

Symbol	Parameter	Value Typ	Unit	Test Conditions
C <sub>IN</sub>	Input Capacitance	4.5	pF	V <sub>CC</sub> = 5.0 V
C <sub>I/O</sub>	Input/Output Capacitance	15	pF	V <sub>CC</sub> = 5.0 V
C <sub>PD</sub>	Power Dissipation Capacitance	45	pF	V <sub>CC</sub> = 5.0 V

## **SWITCHING WAVEFORMS**



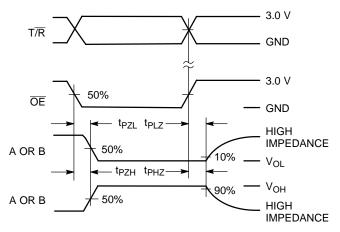
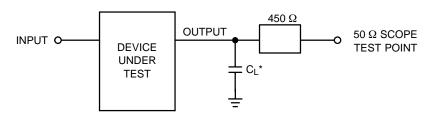


Figure 2.

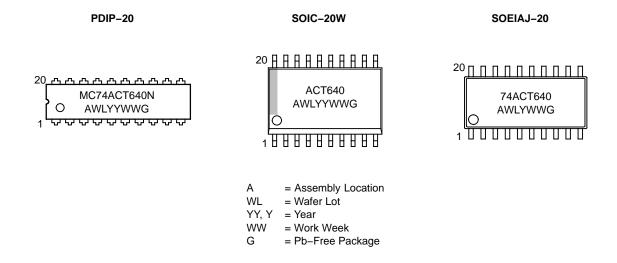
Figure 3.



\*Includes all probe and jig capacitance

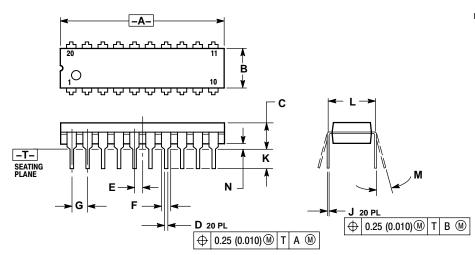
Figure 4. Test Circuit

### **MARKING DIAGRAMS**



### **PACKAGE DIMENSIONS**

PDIP-20 **N SUFFIX** PLASTIC DIP PACKAGE CASE 738-03 ISSUE E



- NOTES:

  1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

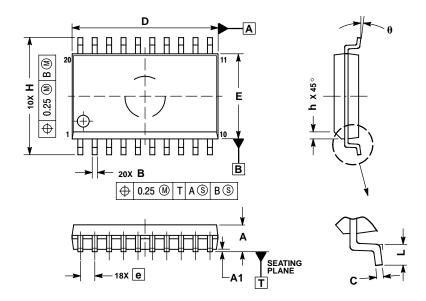
  2. CONTROLLING DIMENSION: INCH.

  3. DIMENSION L TO CENTER OF LEAD WHEN FORMED PARALLEL.

- DIMENSION B DOES NOT INCLUDE MOLD FLASH.

	INC	HES	MILLIN	IETERS	
DIM	MIN	MAX	MIN	MAX	
Α	1.010	1.070	25.66	27.17	
В	0.240	0.260	6.10	6.60	
С	0.150	0.180	3.81	4.57	
D	0.015	0.022	0.39	0.55	
Е	0.050	BSC	1.27 BSC		
F	0.050	0.070	1.27	1.77	
G	0.100	BSC	2.54 BSC		
J	0.008	0.015	0.21	0.38	
K	0.110	0.140	2.80	3.55	
L	0.300 BSC		7.62	BSC	
M	0°	15°	0°	15°	
N	0.020	0.040	0.51	1.01	

## SOIC-20W **DW SUFFIX** CASE 751D-05 **ISSUE G**

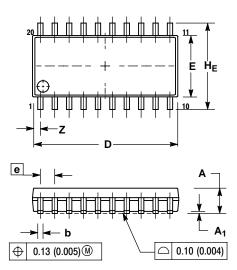


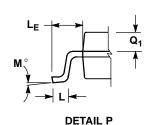
- NOTES:
  1. DIMENSIONS ARE IN MILLIMETERS.
  2. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994.
  3. DIMENSIONS D AND E DO NOT INCLUDE MOLD PROTRUSION.
  4. MAXIMUM MOLD PROTRUSION 0.15 PER SIDE.
  5. DIMENSION B DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.13 TOTAL IN EXCESS OF B DIMENSION AT MAXIMUM MATERIAL CONDITION.

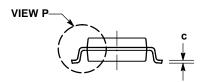
	MILLIMETERS				
DIM	MIN	MAX			
Α	2.35	2.65			
A1	0.10	0.25			
В	0.35	0.49			
С	0.23	0.32			
D	12.65	12.95			
Е	7.40	7.60			
е	1.27	BSC			
Н	10.05	10.55			
h	0.25	0.75			
L	0.50	0.90			
θ	0 °	7 °			

#### PACKAGE DIMENSIONS

## SOEIAJ-20 **M SUFFIX** CASE 967-01 ISSUE A







#### NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: MILLIMETER
  DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH OR PROTRUSIONS AND ARE MEASURED AT THE PARTING LINE. MOLD FLASH OR PROTRUSIONS SHALL NOT EXCEED 0.15
- (0.006) PER SIDE.
  . TERMINAL NUMBERS ARE SHOWN FOR REFERENCE ONLY
- THE LEAD WIDTH DIMENSION (b) DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE LEAD WIDTH
  DIMENSION AT MAXIMUM MATERIAL CONDITION. DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OR THE FOOT. MINIMUM SPACE BETWEEN PROTRUSIONS AND ADJACENT LEAD TO BE 0.46 ( 0.018).

	,	,		
	MILLIMETERS		INC	HES
DIM	MIN	MAX	MIN	MAX
Α		2.05		0.081
A <sub>1</sub>	0.05	0.20	0.002	0.008
b	0.35	0.50	0.014	0.020
С	0.15	0.25	0.006	0.010
D	12.35	12.80	0.486	0.504
E	5.10	5.45	0.201	0.215
е	1.27	BSC	0.050 BSC	
HE	7.40	8.20	0.291	0.323
L	0.50	0.85	0.020	0.033
LE	1.10	1.50	0.043	0.059
М	0 °	10°	0°	10°
Q <sub>1</sub>	0.70	0.90	0.028	0.035
Z		0.81		0.032

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